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**Տեղեկատվական տեխնոլոգիաների կրթական և հետազոտական կենտրոն**
Տեղեկատվական համակարգերի ամբիոն
Professor

## Տեղեկատվական տեխնոլոգիաների կրթական և հետազոտական կենտրոն

Տեղեկատվական համակարգերի ամբիոն

Professor


## Publications

*Patent*

**DETECTION OF ADDRESS ERRORS IN MEMORY DEVICES USING MULTI-SEGMENT ERROR DETECTION CODES**
Samvel Shoukourian, Gurgen Harutyunyan, Hayk Grigoryan, Grigor Tshagharyan, Yervant Zorian

2021

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*Article*

**Memory Physical Aware Multi-Level Fault Diagnosis Flow**
SAMVEL SHOUKOURIAN, GURGEN HARUTYUNYAN, SUREN MARTIROSYAN, YERVANT ZORIAN

IEEE Transactions on Emerging Topics in Computing 2020 700-711

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*Article*

**Fault Awareness for Memory BIST Architecture Shaped by Multidimensional Prediction Mechanism**
S. Shoukourian, G. Harutyunyan, Y. Zorian

IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2019 562-575

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*Patent*

**FINFET-BASED MEMORY TESTING USING MULTIPLE READ OPERATIONS**
Samvel Shoukourian, Gurgen Harutyunyan, Grigor Tshagharyan, Yervant Zorian

2019

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*Article*

**Experimental study on Hamming and Hsiao Codes in the Context of Embedded Applications**
S. Shoukourian, G. Harutyunyan, G. Tshagharyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 25-28

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*Article*

**Automated Flow for Test Pattern Creation for IPs in SoC**
S. Shoukourian, G. Harutyunyan, D. Sargsyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 21-24

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*Article*

**An Efficient Testing Methodology for Embedded Flash Memories**
S. Shoukourian, G. Harutyunyan, S. Martirosyan, Y. Zorian

IEEE East-West Design & Test Symposium 2017 422-425

*Article*

**Security Issues in Test and Repair Infrastructure for Systems-on-Chip**
S. Shoukourian, G. Harutyunyan, G. Tshagharyan

Информационно-коммуникационные технологии в науке, производстве и образовании ICIT-2017 2017 114-122

*Patent*

**Testing Electronic Memories Based on Fault and Test Algorithm Periodicity**
S. Shoukourian, G. Harutyunyan, V. Vardanian, A. Hakhumyan, Y. Zorian

2017

*Conference*

**A power based memory BIST grouping methodology.**
Gurgen Harutyunyan, Samvel K. Shoukourian, Lusine Martirosyan, Yervant Zorian

2015 27-30

http://ieeexplore.ieee.org/xpl/mostRecentIssue.jsp?punumber=7488713

*Conference*

**Overview study on fault modeling and test methodology development for FinFET-based memories.**
Gurgen Harutyunyan, Samvel K. Shoukourian, Grigor Tshagharyan, Yervant Zorian

2015 19-22

http://ieeexplore.ieee.org/xpl/mostRecentIssue.jsp?punumber=7488713

*Conference*

**Extending fault periodicity table for testing faults in memories under 20nm.**
Gurgen Harutyunyan, Samvel K. Shoukourian, Valery A. Vardanian, Yervant Zorian

2014 5-9

http://ieeexplore.ieee.org/xpl/mostRecentIssue.jsp?punumber=7000956